

<IGBT Modules>

# CM150DY-34T

HIGH POWER SWITCHING USE INSULATED TYPE



dual switch (half-bridge)

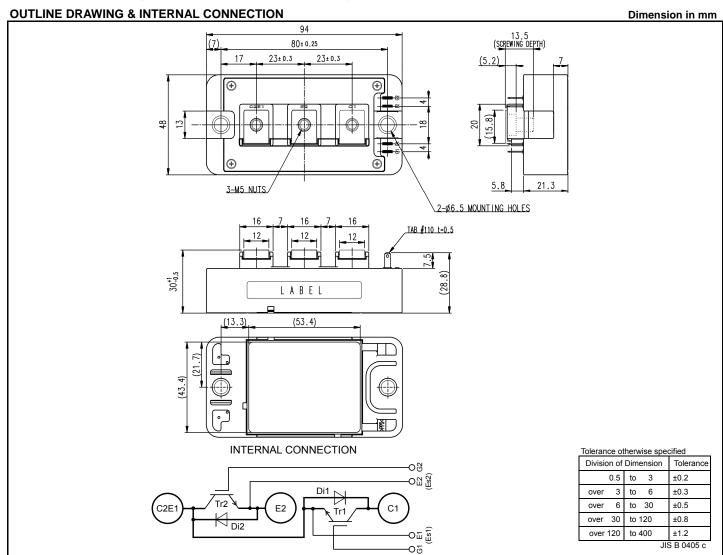
- Flat base type
- Copper base plate (Nickel-plating)
- •Tin-plating signal terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### **APPLICATION**

AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

●PC-TIM (Phase Change Thermal Interface Material) pre-apply



1

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INSULATED TYPE

### MAXIMUM RATINGS (T<sub>vj</sub>=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1700	V	
$V_{\text{GES}}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector current	DC, T <sub>C</sub> =125 °C (Note2, 4)	150	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	300	A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	1865	W	
I <sub>E</sub> (Note1)	Emitter eurrent	DC (Note2)		^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	300	Α	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
$T_{jmax}$	Maximum junction temperature	Instantaneous event (overload)	175	°C	
$T_{Cmax}$	Maximum case temperature	(Note4)	125		
T <sub>jop</sub>	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

### ELECTRICAL CHARACTERISTICS ( $T_{\nu j}$ =25 °C, unless otherwise specified)

Symbol	Itom	Conditions		Limits			Linit
Зуший	Item			Min.	Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μA
$V_{GE(th)}$	Gate-emitter threshold voltage	I <sub>C</sub> =10 mA, V <sub>CE</sub> =10 V			6.0	6.6	V
		I <sub>C</sub> =150 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	2.0	2.45	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.45	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.55	-	
	Collector-emitter saturation voltage	I <sub>C</sub> =150 A,	T <sub>vj</sub> =25 °C	-	1.95	2.35	V
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	2.35	-	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	2.45	-	
Cies	Input capacitance		•	-	-	41.3	nF
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	1.1	
Cres	Reverse transfer capacitance	1 32 /		-	-	0.4	1
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =1000 V, I <sub>C</sub> =150 A, V <sub>GE</sub> =15 V		-	1.24	-	μC
t <sub>d(on)</sub>	Turn-on delay time	$V_{CC}$ =1000 V, $I_{C}$ =150 A, $V_{GE}$ =±15 V, $R_{G}$ =0 Ω, Inductive load		-	-	800	ns
t <sub>r</sub>	Rise time			-	-	200	
t <sub>d(off)</sub>	Turn-off delay time			-	-	800	
t <sub>f</sub>	Fall time			-	-	600	
(Nata 4)		I <sub>E</sub> =150 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.75	3.35	V
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	3.0	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	3.0	-	
(Nata 4)	- Emitter-collector voltage	I <sub>E</sub> =150 A,	T <sub>vj</sub> =25 °C	-	2.65	3.20	
V <sub>EC</sub> (Note.1)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	2.75	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	2.75	-	1
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =1000 V, I <sub>E</sub> =150 A, V <sub>GE</sub> =±15 V,		-	-	300	ns
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=0 \Omega$ , Inductive load		-	7.5	-	μC
Eon	Turn-on switching energy per pulse	$V_{CC}$ =1000 V, $I_{C}$ = $I_{E}$ =150 A, $V_{GE}$ =±15 V, $R_{G}$ =0 $\Omega$ , $T_{vj}$ =150 °C,		-	38.6	-	
E <sub>off</sub>	Turn-off switching energy per pulse			-	44.5	-	mJ
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load		-	17.2	-	mJ
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.3	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch		-	5.0	-	Ω

### HIGH POWER SWITCHING USE

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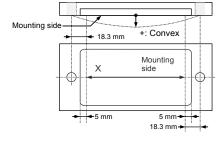
#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Itam	Conditions	Limits			Linit
	ltem	Conditions	Min.	Тур.	Max.	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	80.3	K/kW
$R_{th(j-c)D}$	Thermal resistance	Junction to case, per Inverter FWD (Note4)	-	-	115.5	N/KVV
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4, 6)	-	24.0	-	K/kW
	Contact thermal resistance	per 1 module, PC-TIM applied (Note4, 7)	-	6.3	-	K/KVV

#### **MECHANICAL CHARACTERISTICS**

Symbol	Itom	Conditions		Limits			Unit
	Item			Min.	Тур.	Max.	Offic
M <sub>t</sub>	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N·m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N·m
d	Creepage distance	Terminal to terminal		18	-	-	- mm
d <sub>s</sub>		Terminal to base plate		21.1	-	-	
da	Clearance	Terminal to terminal		9.6	-	-	
	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline X, Y (Note8)		±0	-	+200	μm
m	mass	-		-	155	-	g

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
  - 2. Junction temperature  $(T_{vj})$  should not increase beyond  $T_{vjmax}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vjmax}$  rating.
  - 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 7. Typical value is measured by using PC-TIM of  $\lambda = 3.4$  W/(m·K)/D<sub>(C-S)</sub>=50  $\mu m.$
  - 8. The base plate (mounting side) flatness measurement points (X, Y) are shown in the following figure.



#### HIGH POWER SWITCHING USE

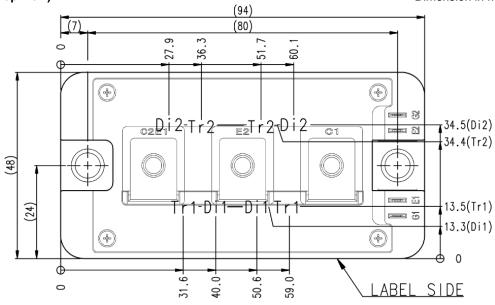
**INSULATED TYPE** 

#### **RECMENDED OPERATING CONDITIONS**

Symbol	ltom	Conditions	Limits			Linit
	Item	Conditions	Min.	Тур.	Max.	Unit V
Vcc	(DC) Supply voltage	Applied across C1-E2 terminals	-	1000	1200	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	0	-	56	Ω

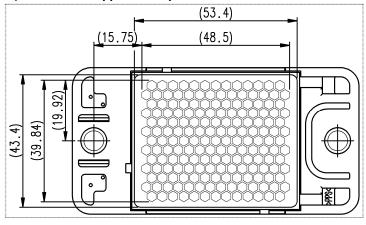
#### **CHIP LOCATION (Top view)**

Dimension in mm, tolerance: ±1 mm

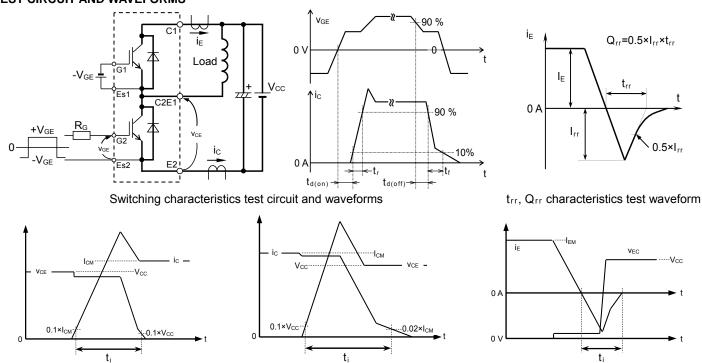


Tr1/Tr2: IGBT, Di1/Di2: FWD

#### Option: PC-TIM applied baseplate outline



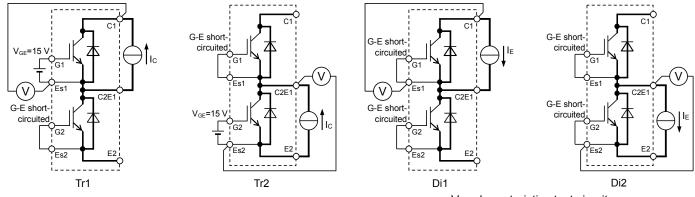
#### **TEST CIRCUIT AND WAVEFORMS**



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **TEST CIRCUIT**

IGBT Turn-on switching energy



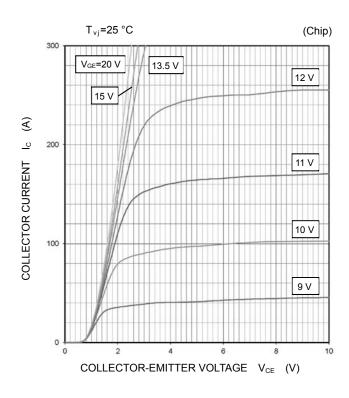
V<sub>CEsat</sub> characteristics test circuit

V<sub>EC</sub> characteristics test circuit

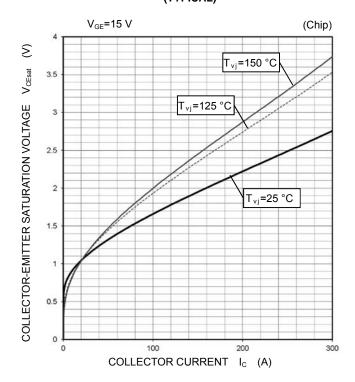
FWD Reverse recovery energy

#### **PERFORMANCE CURVES**

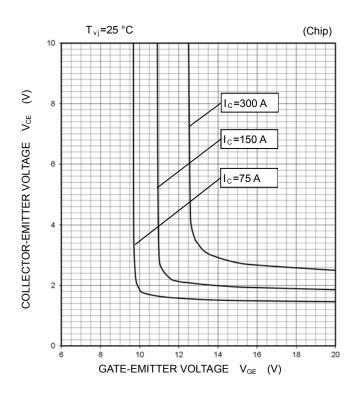
# OUTPUT CHARACTERISTICS (TYPICAL)



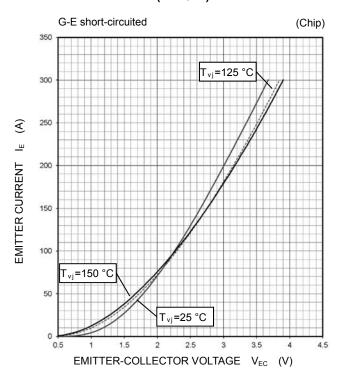
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



# COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)

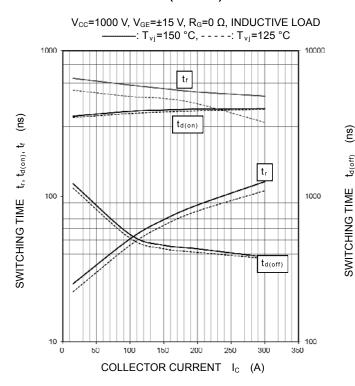


#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

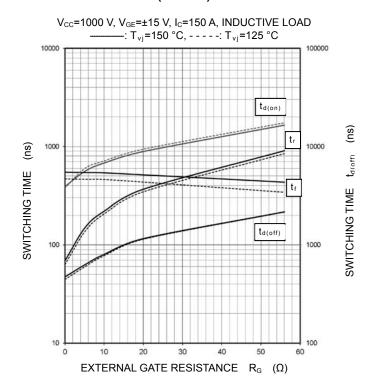


#### **PERFORMANCE CURVES**

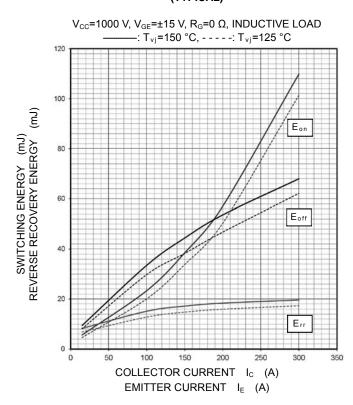
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



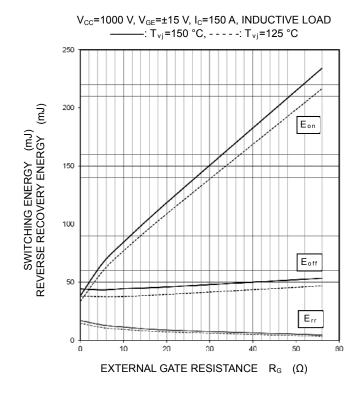
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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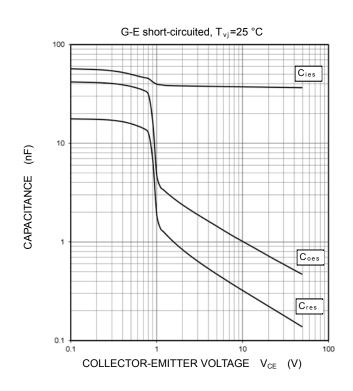


# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

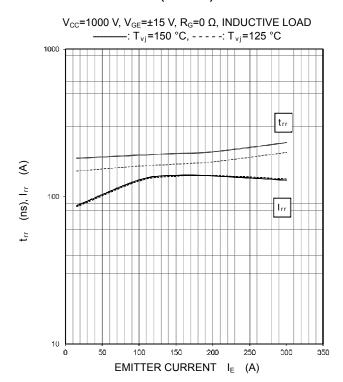


#### **PERFORMANCE CURVES**

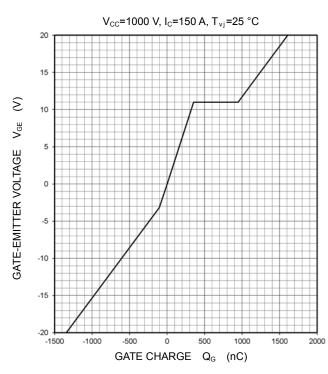
# CAPACITANCE CHARACTERISTICS (TYPICAL)



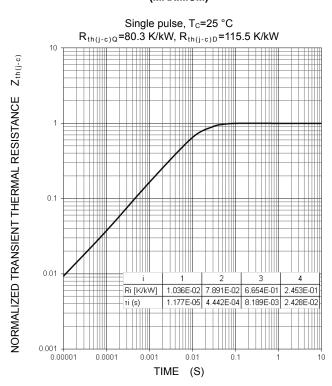
# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



# GATE CHARGE CHARACTERISTICS (TYPICAL)



# TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

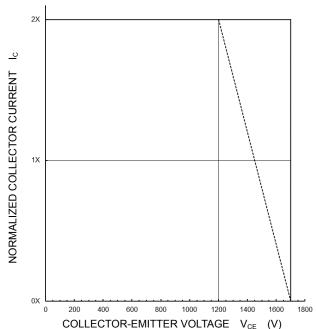
HIGH POWER SWITCHING USE

#### **INSULATED TYPE**

#### **PERFORMANCE CURVES**

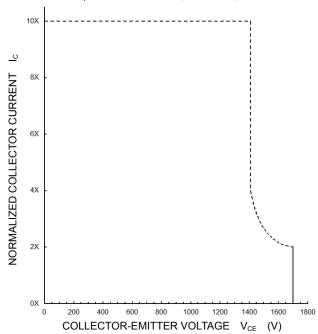
#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)

 $V_{\text{CC}}$ ≤1200 V,  $V_{\text{GE}}$ =±15 V,  $R_{\text{G}}$ =0~56 Ω, ———:  $T_{\text{v}_{\text{I}}}$ =25~150 °C (Normal load operations (Continuous) -----:  $T_{\text{v}_{\text{I}}}$ =175 °C (Unusual load operations (Limited period)



# SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{CC}{\le}1200$  V,  $V_{GE}{=}{\pm}15$  V,  $R_{G}{=}0{\sim}56$   $\Omega,$   $T_{vj}{=}$  25  $\sim$  150 °C,  $t_{W}{\le}8$  µs, Non-Repetitive



HIGH POWER SWITCHING USE

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### Keep safety first in your circuit designs!

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